

## 54F/74F379 Quad Parallel Register with Enable

### General Description

The 'F379 is a 4-bit register with buffered common Enable. This device is similar to the 'F175 but features the common Enable rather than common Master Reset.

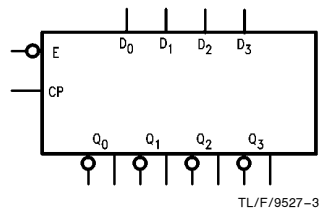
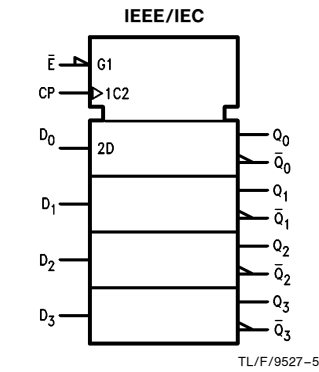
### Features

- Edge triggered D-type inputs
- Buffered positive edge-triggered clock
- Buffered common enable input
- True and complement outputs
- Guaranteed 4000V minimum ESD protection

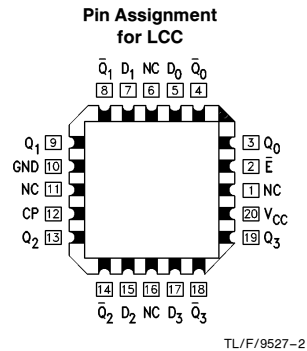
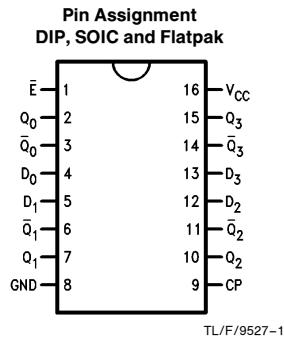
Commercial	Military	Package Number	Package Description
74F379PC		N16E	16-Lead (0.300" Wide) Molded Dual-In-Line
	54F379DM (QB)	J16A	16-Lead Ceramic Dual-In-Line
74F379SC (Note 1)		M16A	16-Lead (0.300" Wide) Molded Small Outline, JEDEC
74F379SJ (Note 1)		M16D	16-Lead (0.300" Wide) Molded Small Outline, EIAJ
	54F379FM (QB)	W16A	16-Lead Cerpack
	54F379LM (QB)	E20A	20-Lead Ceramic Leadless Chip Carrier, Type C

Note 1: Devices also available in 13" reel. Use suffix = SCX and SJX.

### Logic Symbols



### Connection Diagrams



TRI-STATE® is a registered trademark of National Semiconductor Corporation.

## Unit Loading/Fan Out

Pin Names	Description	54F/74F	
		U.L. HIGH/LOW	Input $I_{IH}/I_{IL}$ Output $I_{OH}/I_{OL}$
$\bar{E}$	Enable Input (Active LOW)	1.0/1.0	20 $\mu$ A/ -0.6 mA
$D_0$ - $D_3$	Data Inputs	1.0/1.0	20 $\mu$ A/ -0.6 mA
CP	Clock Pulse Input (Active Rising Edge)	1.0/1.0	20 $\mu$ A/ -0.6 mA
$Q_0$ - $Q_3$	Flip-Flop Outputs	50/33.3	-1 mA/20 mA
$\bar{Q}_0$ - $\bar{Q}_3$	Complement Outputs	50/33.3	-1 mA/20 mA

## Functional Description

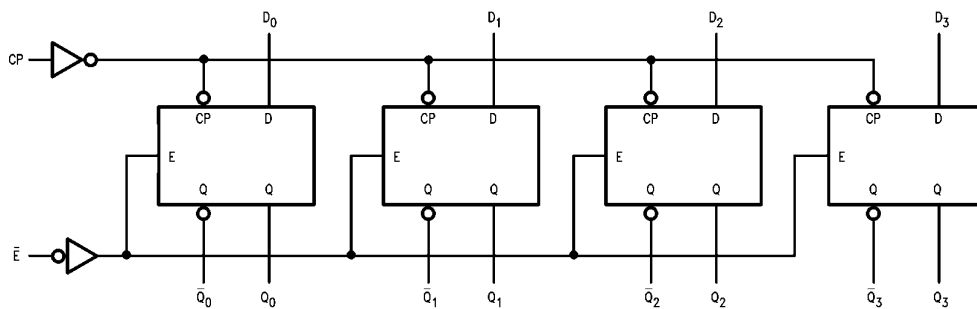
The 'F379 consists of four edge-triggered D-Type flip-flops with individual D inputs and Q and  $\bar{Q}$  outputs. The Clock (CP) and Enable ( $\bar{E}$ ) inputs are common to all flip-flops. When the  $\bar{E}$  is input HIGH, the register will retain the present data independent of the CP input. The  $D_n$  and  $\bar{E}$  inputs can change when the clock is in either state, provided that the recommended setup and hold times are observed.

## Truth Table

Inputs			Outputs	
$\bar{E}$	CP	$D_n$	$Q_n$	$\bar{Q}_n$
H	—	X	NC	NC
L	—	H	H	L
L	—	L	L	H

H = HIGH Voltage Level  
 L = LOW Voltage Level  
 X = Immaterial  
 — = LOW-to-HIGH Transition  
 NC = No Change

## Logic Diagram



TL/F/9527-4

Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	-55°C to +125°C
Junction Temperature under Bias	-55°C to +175°C
Plastic	-55°C to +150°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output in HIGH State (with V <sub>CC</sub> = 0V)	
Standard Output	-0.5V to V <sub>CC</sub>
TRI-STATE® Output	-0.5V to +5.5V
Current Applied to Output in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)
ESD Last Passing Voltage (Min)	4000V

**Note 1:** Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

**Note 2:** Either voltage limit or current limit is sufficient to protect inputs.

## Recommended Operating Conditions

Free Air Ambient Temperature	
Military	-55°C to +125°C
Commercial	0°C to +70°C
Supply Voltage	
Military	+4.5V to +5.5V
Commercial	+4.5V to +5.5V

## DC Electrical Characteristics

Symbol	Parameter	54F/74F			Units	V <sub>CC</sub>	Conditions
		Min	Typ	Max			
V <sub>IH</sub>	Input HIGH Voltage	2.0			V		Recognized as a HIGH Signal
V <sub>IL</sub>	Input LOW Voltage	0.8			V		Recognized as a LOW Signal
V <sub>CD</sub>	Input Clamp Diode Voltage	-1.2			V	Min	I <sub>IN</sub> = -18 mA
V <sub>OH</sub>	Output HIGH Voltage	54F	10% V <sub>CC</sub>	2.5	V	Min	I <sub>OH</sub> = -1 mA I <sub>OH</sub> = -1 mA I <sub>OH</sub> = -1 mA
		74F	10% V <sub>CC</sub>	2.5			
		74F	5% V <sub>CC</sub>	2.7			
V <sub>OL</sub>	Output LOW Voltage	54F	10% V <sub>CC</sub>	0.5	V	Min	I <sub>OL</sub> = 20 mA I <sub>OL</sub> = 20 mA
		74F	10% V <sub>CC</sub>	0.5			
I <sub>IH</sub>	Input HIGH Current	54F		20.0	μA	Max	V <sub>IN</sub> = 2.7V
		74F		5.0			
I <sub>BVI</sub>	Input HIGH Current Breakdown Test	54F		100	μA	Max	V <sub>IN</sub> = 7.0V
		74F		7.0			
I <sub>CEX</sub>	Output HIGH Leakage Current	54F		250	μA	Max	V <sub>OUT</sub> = V <sub>CC</sub>
		74F		50			
V <sub>ID</sub>	Input Leakage Test	74F	4.75		V	0.0	I <sub>ID</sub> = 1.9 μA All Other Pins Grounded
I <sub>OD</sub>	Output Leakage Circuit Current	74F		3.75	μA	0.0	V <sub>IOD</sub> = 150 mV All Other Pins Grounded
I <sub>IL</sub>	Input LOW Current			-0.6	mA	Max	V <sub>IN</sub> = 0.5V
I <sub>OS</sub>	Output Short-Circuit Current			-60	mA	Max	V <sub>OUT</sub> = 0V
I <sub>CCL</sub>	Power Supply Current			28	mA	Max	V <sub>O</sub> = LOW

## AC Electrical Characteristics

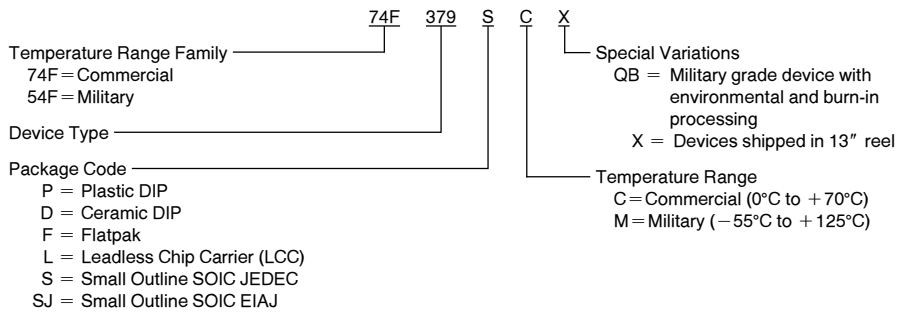
Symbol	Parameter	74F			54F		74F		Units
		T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V C <sub>L</sub> = 50 pF			T <sub>A</sub> , V <sub>CC</sub> = Mil C <sub>L</sub> = 50 pF		T <sub>A</sub> , V <sub>CC</sub> = Com C <sub>L</sub> = 50 pF		
		Min	Typ	Max	Min	Max	Min	Max	
f <sub>max</sub>	Maximum Clock Frequency	100	140	6.5	75		100		MHz
t <sub>PLH</sub>	Propagation Delay	3.5	5.0	6.5	3.0	8.5	3.5	7.5	ns
t <sub>PHL</sub>	CP to Q <sub>n</sub> , $\bar{Q}_n$	5.0	6.5	8.5	4.0	10.0	5.0	9.5	

## AC Operating Requirements

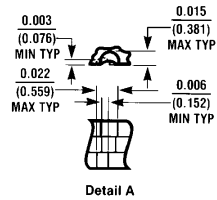
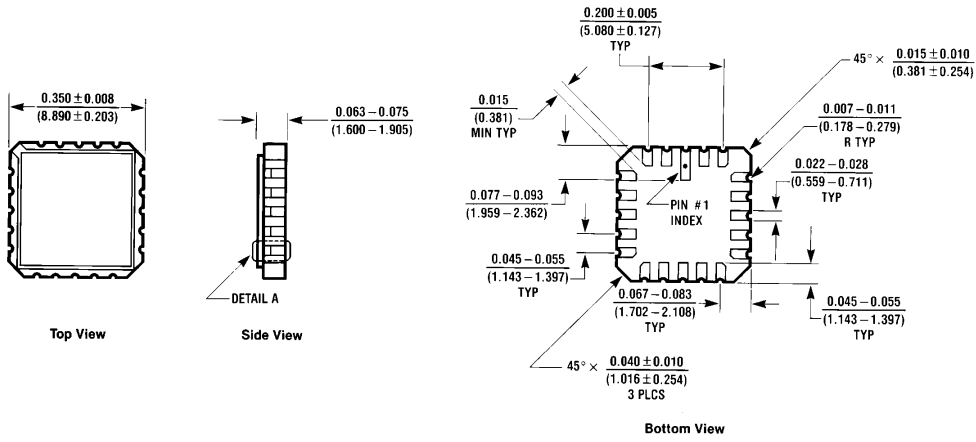
Symbol	Parameter	74F		54F		74F		Units
		T <sub>A</sub> = +25°C V <sub>CC</sub> = +5.0V		T <sub>A</sub> , V <sub>CC</sub> = Mil		T <sub>A</sub> , V <sub>CC</sub> = Com		
		Min	Max	Min	Max	Min	Max	
t <sub>s</sub> (H)	Setup Time, HIGH or LOW	3.0		4.0			3.0	ns
t <sub>s</sub> (L)	D <sub>n</sub> to CP	3.0		4.0			3.0	
t <sub>h</sub> (H)	Hold Time, HIGH or LOW	1.0		2.0			1.0	ns
t <sub>h</sub> (L)	D <sub>n</sub> to CP	1.0		2.0			1.0	
t <sub>s</sub> (H)	Setup Time, HIGH or LOW	6.0		8.0			6.0	ns
t <sub>s</sub> (L)	$\bar{E}$ to CP	6.0		8.0			6.0	
t <sub>h</sub> (H)	Hold Time, HIGH or LOW	0		0			0	ns
t <sub>h</sub> (L)	$\bar{E}$ to CP	0		0			0	
t <sub>w</sub> (H)	CP Pulse Width	4.0		5.0			4.0	ns
t <sub>w</sub> (L)	HIGH or LOW	5.0		7.0			5.0	

## Ordering Information

The device number is used to form part of a simplified purchasing code where the package type and temperature range are defined as follows:

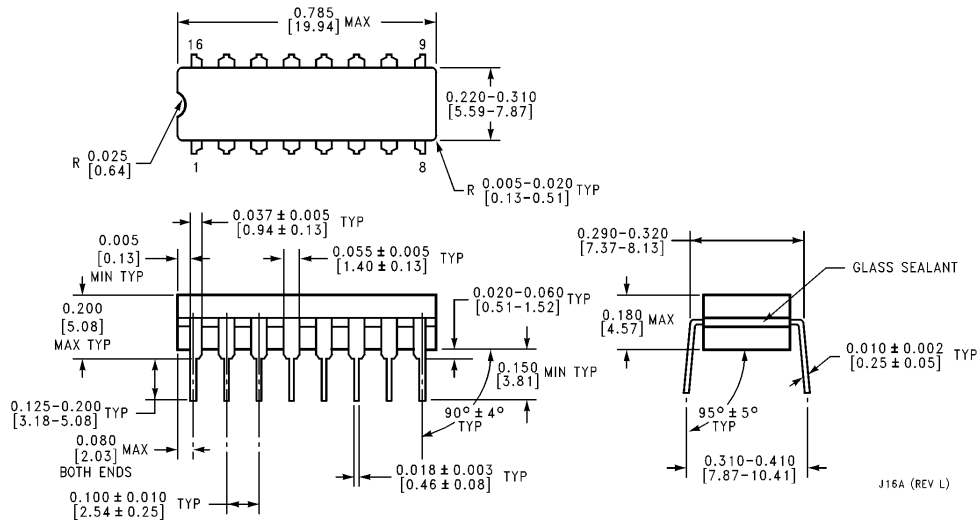


**Physical Dimensions** inches (millimeters)



**20-Lead Ceramic Leadless Chip Carrier (L)**  
**NS Package Number E20A**

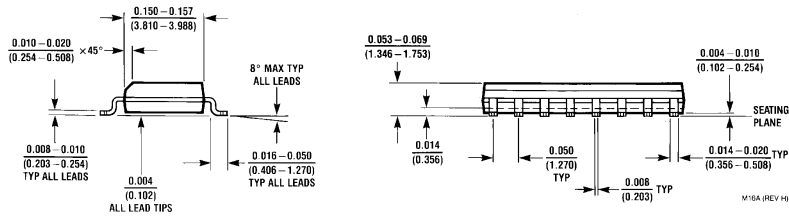
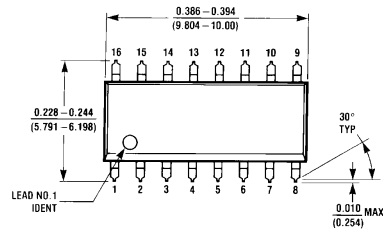
E20A (REV D)



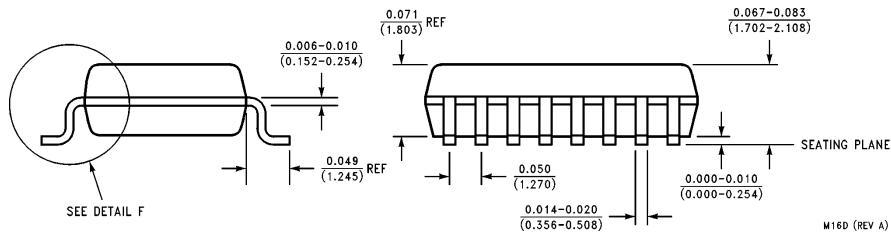
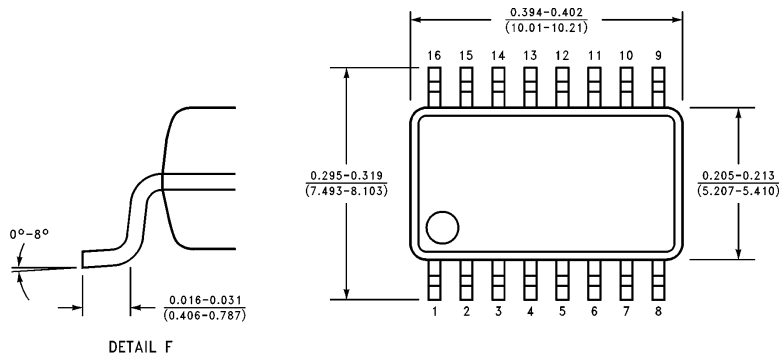
**16-Lead Ceramic Dual-In-Line Package (D)**  
**NS Package Number J16A**

J16A (REV L)

**Physical Dimensions** inches (millimeters) (Continued)

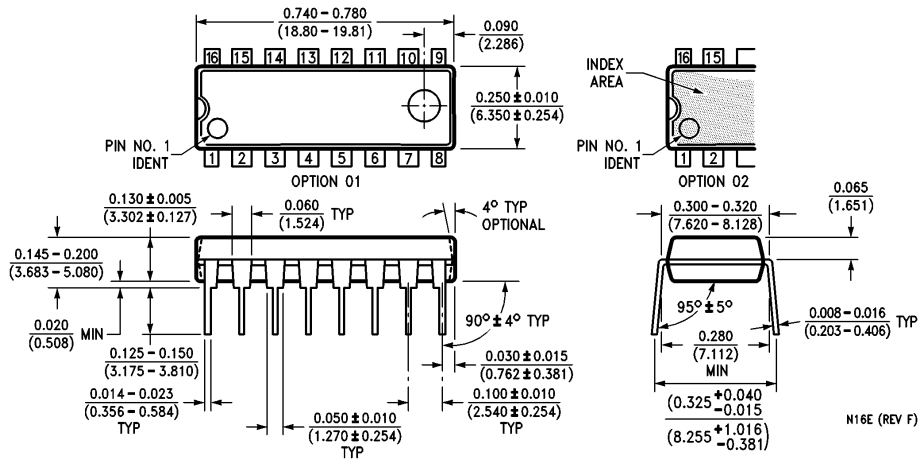


**16-Lead (0.150" Wide) Molded Small Outline Integrated Circuit (S)**  
NS Package Number M16A



**16-Lead (0.300" Wide) Molded Small Outline Package, EIAJ (SJ)**  
NS Package Number M16D

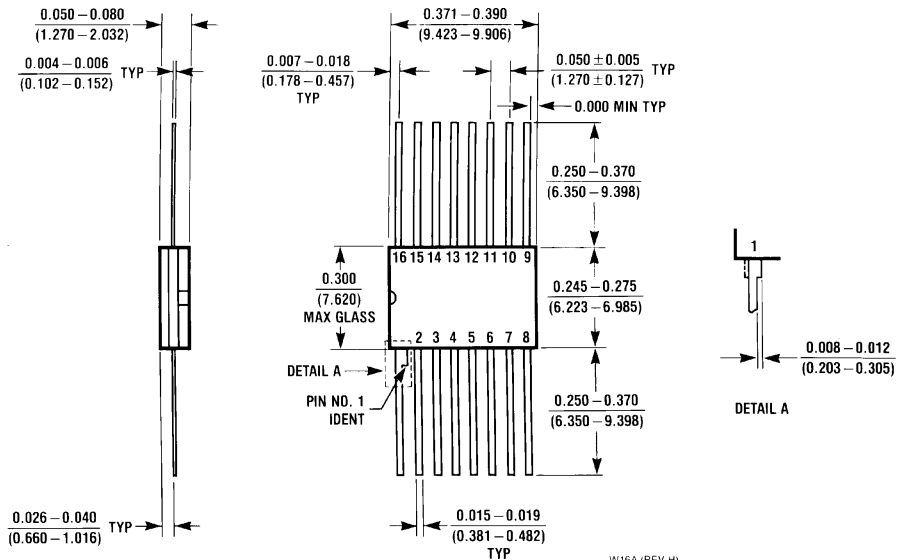
**Physical Dimensions** inches (millimeters) (Continued)



**16-Lead (0.300" Wide) Molded Dual-In-Line Package (P)**  
**NS Package Number N16E**

N16E (REV F)

**Physical Dimensions** inches (millimeters) (Continued)



**16-Lead Ceramic Flatpak (F)  
NS Package Number W16A**

**LIFE SUPPORT POLICY**

NATIONAL'S PRODUCTS ARE NOT AUTHORIZED FOR USE AS CRITICAL COMPONENTS IN LIFE SUPPORT DEVICES OR SYSTEMS WITHOUT THE EXPRESS WRITTEN APPROVAL OF THE PRESIDENT OF NATIONAL SEMICONDUCTOR CORPORATION. As used herein:

1. Life support devices or systems are devices or systems which, (a) are intended for surgical implant into the body, or (b) support or sustain life, and whose failure to perform, when properly used in accordance with instructions for use provided in the labeling, can be reasonably expected to result in a significant injury to the user.
2. A critical component is any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.



**National Semiconductor Corporation**  
1111 West Bardin Road  
Arlington, TX 76017  
Tel: 1(800) 272-9959  
Fax: 1(800) 737-7018

**National Semiconductor Europe**  
Fax: (+49) 0-180-530 85 86  
Email: cnjwge@tevm2.nsc.com  
Deutsch Tel: (+49) 0-180-530 85 85  
English Tel: (+49) 0-180-532 78 32  
Français Tel: (+49) 0-180-532 93 58  
Italiano Tel: (+49) 0-180-534 16 80

**National Semiconductor Hong Kong Ltd.**  
13th Floor, Straight Block,  
Ocean Centre, 5 Canton Rd.  
Tsimshatsui, Kowloon  
Hong Kong  
Tel: (852) 2737-1600  
Fax: (852) 2736-9960

**National Semiconductor Japan Ltd.**  
Tel: 81-043-299-2309  
Fax: 81-043-299-2408

National does not assume any responsibility for use of any circuitry described, no circuit patent licenses are implied and National reserves the right at any time without notice to change said circuitry and specifications.